



# Quad 2-Input AND Gate

**ELECTRICALLY TESTED PER:  
5962-8750401**

The 10H504 is a quad 2-input **AND** gate. One of the gates has both **AND/ NAND** outputs available.

This MECL 10H part is a functional/pinout duplication of the standard MECL 10K family part, with 100% improvement in propagation delay, and no increase in power-supply current.

- Propagation Delay, 1.0 ns Typical
- 55 mW Max/Gate (No Load)
- Improved Noise Margin 150 mV (Over Operating Voltage and Temperature Range)
- Voltage Compensated
- MECL 10K-Compatible

### PIN ASSIGNMENTS

FUNCTION	DIL	FLATS	LCC	BURN-IN (CONDITION C)
VCC1	1	5	2	GND
AOUT	2	6	3	51 Ω to V <sub>TT</sub>
BOUT	3	7	4	51 Ω to V <sub>TT</sub>
A <sub>IN</sub>	4	8	5	GND
A <sub>IN</sub>	5	9	7	GND
B <sub>IN</sub>	6	10	8	GND
B <sub>IN</sub>	7	11	9	GND
VEE	8	12	10	VEE
$\overline{DOUT}$	9	13	12	51 Ω to V <sub>TT</sub>
C <sub>IN</sub>	10	14	13	GND
C <sub>IN</sub>	11	15	14	GND
D <sub>IN</sub>	12	16	15	GND
D <sub>IN</sub>	13	1	17	GND
COUT	14	2	18	51 Ω to V <sub>TT</sub>
DOUT	15	3	19	51 Ω to V <sub>TT</sub>
VCC2	16	4	20	GND

### BURN - IN CONDITIONS:

V<sub>TT</sub> = -2.0 V MAX / -2.2 V MIN

VEE = -5.7 V MAX / -5.2 V MIN

## Military 10H504

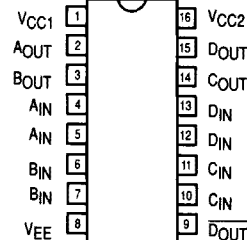


### AVAILABLE AS

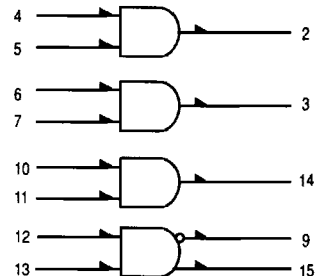
- 1) JAN: N/A
  - 2) SMD: 5962-8750401
  - 3) 883: 10H504/BXAJC
- X = CASE OUTLINE AS FOLLOWS:

PACKAGE: CERDIP: E  
CERFLAT: F  
LCC: 2

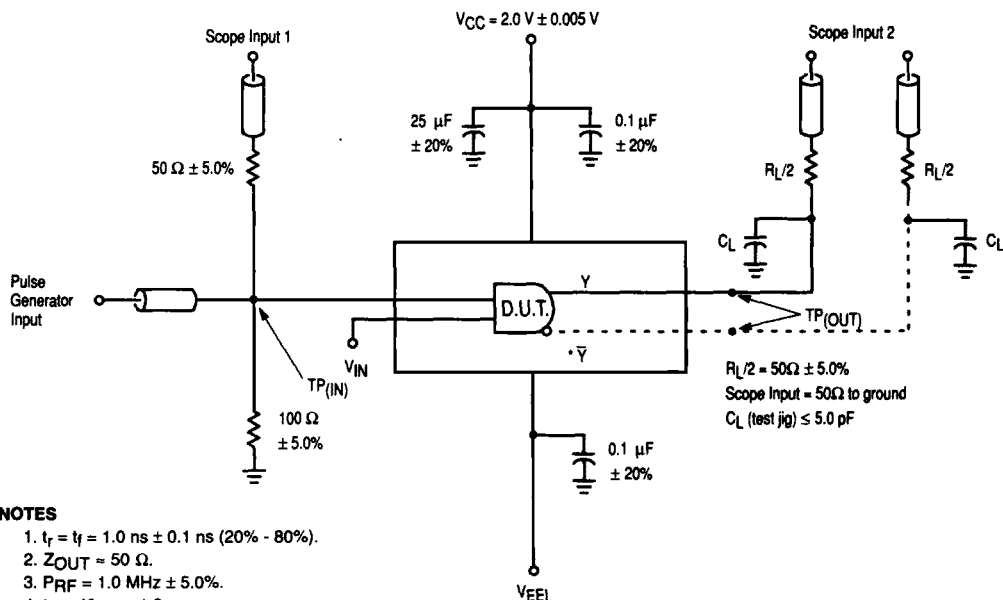
The letter "M" appears before the slash on LCC.



### LOGIC DIAGRAM



# 10H504



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## NOTES

1. Perform test in accordance with test table; each output is tested separately.
2. All input and output cables to the scope are equal lengths of  $50 \Omega$  coaxial cable. Wire length should be  $\leq 0.250$  inches (6.35 mm) from  $TP_{IN}$  to input pin and  $TP_{OUT}$  to output pin.
3. Outputs not under test should be connected to a  $100 \Omega$  resistor to ground.
4. \* Applies to gate 4 only.

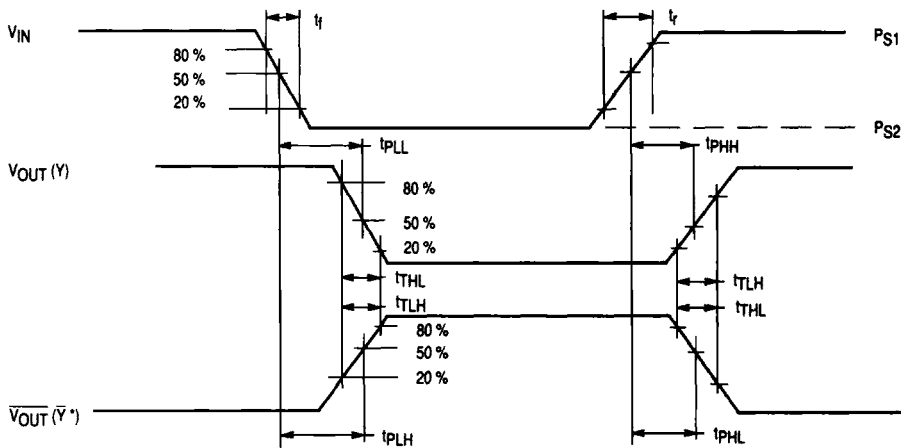


Figure 1. Switching Test Circuit and Waveforms

# 10H504 QUIESCENT LIMIT TABLE \*

## \* ELECTRICAL CHARACTERISTICS

Each MECL 10H series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 100 Ω resistor to - 2.0 volts.

Test Temperature	Test Voltage Values (Volts)							
	V <sub>IH1</sub>	V <sub>IL1</sub>	V <sub>IH2</sub>	V <sub>IL2</sub>	PS1	PS2	VEE1	VEE2
T <sub>A</sub> = 25 °C	-0.78	-1.95	-1.13	-1.480	+1.11	+0.31	-5.46	-4.94
T <sub>A</sub> = 125 °C	-0.85	-1.95	-0.96	-1.465	+1.24	+0.36	-5.46	-4.94
T <sub>A</sub> = -55 °C	-0.84	-1.95	-1.16	-1.510	+1.01	+0.28	-5.46	-4.94

Symbol	Parameter	Limits						Units	TEST VOLTAGE APPLIED TO PINS BELOW							
		+ 25 °C		+ 125 °C		- 55 °C			Pinouts referenced are for DIL package, check Pin Assignments V <sub>CC</sub> = 0 V, Output Load = 100 Ω to -2.0 V							
		Subgroup 1		Subgroup 2		Subgroup 3										
		Min	Max	Min	Max	Min	Max	V <sub>IH1</sub>	V <sub>IL1</sub>	V <sub>IH2</sub>	V <sub>IL2</sub>	VEE1	VEE2	V <sub>CC</sub>	P.U.T.	
V <sub>OH</sub>	High Output Voltage	-1.01	-0.78	-0.86	-0.65	-1.06	-0.84	4-7 10-13				8		1, 16	2, 3, 9, 14, 15	
V <sub>OL</sub>	Low Output Voltage	-1.95	-1.58	-1.95	-1.565	-1.95	-1.61	4-7 10-13				8		1, 16	2, 3, 9, 14, 15	
V <sub>OH1</sub>	High Output Voltage	-1.01	-0.78	-0.86	-0.65	-1.06	-0.84	4-7 10-13		4-7 10-13	12, 13	8	8	1, 16	2, 3, 9, 14, 15	
V <sub>OL1</sub>	Low Output Voltage	-1.95	-1.58	-1.95	-1.565	-1.95	-1.61	5-7 10-13		12, 13	4-7 10-13	8	8	1, 16	2, 3, 9, 14, 15	
I <sub>EE</sub>	Power Supply Current	-35		-39		-39						8		1, 16	8	
I <sub>IH</sub>	Input Current High	220		350		350		5, 6 11, 12				8		1, 16	5, 6, 11, 12	
I <sub>IH1</sub>	Input Current High	265		425		425		4, 7 10, 13				8		1, 16	4, 7, 10, 13	
I <sub>IL</sub>	Input Current Low	0.5		0.3		0.5		4, 7, 10 12, 13					8	1, 16	4-7, 10-13	

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## \* ELECTRICAL CHARACTERISTICS

Each MECL 10H series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 100 Ω resistor to - 2.0 volts.

Test Temperature	Test Voltage Values (Volts)									
	VIH1	VIL1	VIH2	VIL2	PS1	PS2	VEE1	VEE2	VEEL	VEEL
TA = 25 °C	-0.78	-1.95	-1.13	-1.480	+1.11	+0.31	-5.46	-4.94	-2.94	-2.94
TA = 125 °C	-0.65	-1.95	-0.96	-1.465	+1.24	+0.36	-5.46	-4.94	-2.94	-2.94
TA = -55 °C	-0.84	-1.95	-1.16	-1.510	+1.01	+0.28	-5.46	-4.94	-2.94	-2.94

Symbol	Parameter	Limits						Units	TEST VOLTAGE APPLIED TO PINS BELOW					
		+ 25 °C		+ 125 °C		- 55 °C			Pinouts referenced are for DIL package, check Pin Assignments VCC = 2.0 V, Output Load = 100 Ω to GND					
		Subgroup 9	Subgroup 10	Subgroup 9	Subgroup 10	Subgroup 11	VIN		VOUT	VIH2	VCC	VEEL	P.U.T.	
t <sub>TLH</sub>	Rise Time	0.3	1.5	0.6	1.65	0.3	1.4	ns	4	2	5	1, 16	8	3, 9, 14, 15
t <sub>THL</sub>	Fall time	0.3	1.5	0.6	1.65	0.3	1.4	ns	4	2	5	1, 16	8	3, 9, 14, 15
t <sub>pHL</sub>	Propagation Delay High to Low	0.55	1.9	0.45	1.9	0.4	1.7	ns	4	2	5	1, 16	8	3, 9, 14, 15
t <sub>pHH</sub>	Propagation Delay High to High	0.5	1.7	0.55	1.8	0.4	1.55	ns	4	2	5	1, 16	8	2, 3, 9, 14
t <sub>pLL</sub>	Propagation Delay Low to Low	0.4	1.6	0.45	1.75	0.4	1.6	ns	4	2	5	1, 16	8	2, 3, 9, 14, 15
t <sub>pLH</sub>	Propagation Delay Low to High	0.4	1.4	0.45	1.7	0.4	1.4	ns	13	9	12	1, 16	8	2, 3, 9, 14, 15